

<b>Notice of References Cited</b>	Application/Control No. 10/707,069		Applicant(s)/Patent Under Reexamination VOLDMAN, STEVEN H.	
	Examiner Nghia M. Doan		Art Unit 2825	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,901,065	05-1999	Guruswamy et al.	716/8
	B	US-6,878,595	04-2005	Spratt, James P	438/288
	C	US-2004/0147080	07-2004	Spratt, James P.	438/289
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Ming-Dou Ker and Jeng-Jie Peng, Layout Design and Verification for Cell Library to Improve ESD/ Latchup Reliability in Deep-Submicro CMOS Technology, IEEE, Custom Integrated Circuit Conference, pg. 537-540, 1998
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.